

4/17/2013



**RELIABILITY MONITOR REPORT
FOR**

MFN 0.8 μ m Silicon Gate CMOS (C3)

MAXIM INTEGRATED

**160 RIO ROBLES
SAN JOSE, CA 95134**

**This Report was prepared by
MAXIM INTEGRATED Reliability Engineering**

Summary:

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

MAX3222CUP+	MAX3225EUP+
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The calculated failure rate for devices using this process is:

FAILURE RATE: MTTF (YRS): 5879 QUANTITY: 158 FAILS: 0 FITS: 19.4

The parameters used to calculate this failure rate are as follows:

Cf: 60% Ea: 0.7 Tu: 25 °C

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 4/1/2012 and 3/31/2013 .

Process Information:

Process Description: MFN 0.8µm Silicon Gate CMOS (C3)

OPERATING LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE	1140	MAX3222CUP+	135°C	192 HRS	78	0	JABA2Q001AA
HIGH TEMP OP LIFE	1140	MAX3225EUP+	135°C	192 HRS	80	0	J2DVBQ001AQ
Total:						0	

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